

# MOSFET (MISFET, IGFET)



ELEC 424

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# Field Effect Transistors

- ◆ Proposed in the 1930's by Lilienfeld
  - Not practical because of role of surface defects/states
- ◆ Bardeen and Brattain were trying to demonstrate an FET when they serendipitously invented the point contact bipolar transistor.
  - Shockley extended the FET concept to the BJT
- ◆ First MOSFET finally happened in 1960

# Bipolar vs Unipolar

- ◆ P-N Junction Dominate Features
  - Minority carrier injection at forward bias
  - Depletion width modulation at reverse bias
- ◆ Bipolar devices rely primarily on minority carrier injection across the narrow base region.
- ◆ Both hole and electron current matter, so they are called BIPOLAR devices.
- ◆ Junction FETs rely primarily on reverse bias to control channel width, and subsequently majority carrier current.
- ◆ FETs are sometimes called UNIPOLAR devices.

# Similar but Different

## ◆ BJT and FETs

- Both three terminal devices
- Current through two terminals is regulated by the third

## ◆ BUT

- Base *current* controls emitter/collector current in BJTs
- Gate *voltage* controls source/drain current in FETs

# What Transistors Do

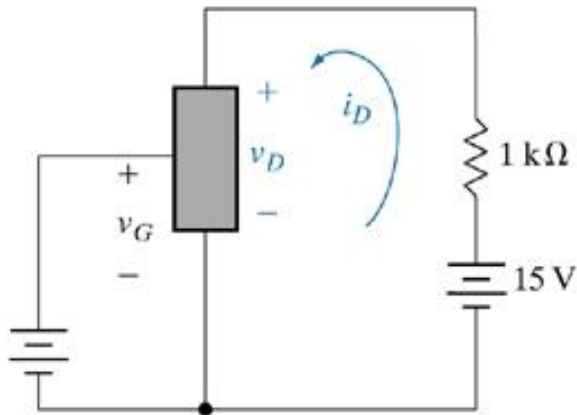
## ◆ Amplify

- The electrical character of the source/drain or emitter/collector is a *reflection of the character of the gate or base, but increased or decreased by a gain factor.*

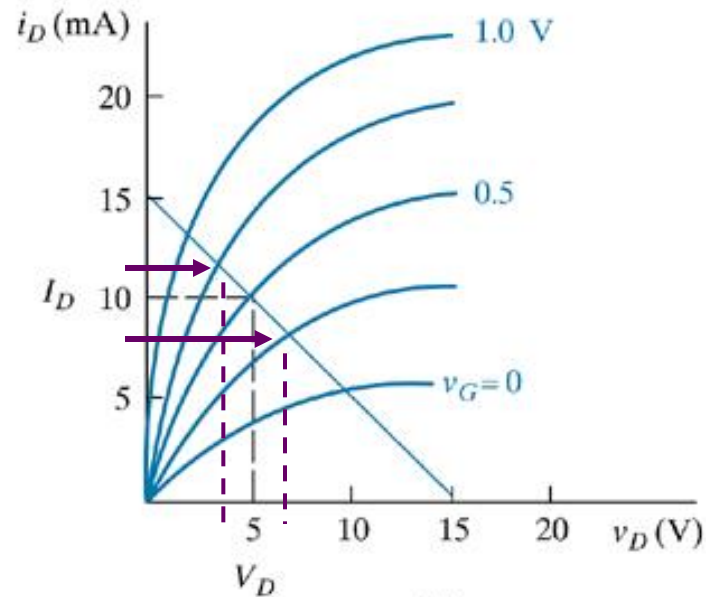
## ◆ Switch

- Source/drain or emitter/collector current can be *turned on or off* by applying the proper signal to the gate or base.

# Amplification



(a)



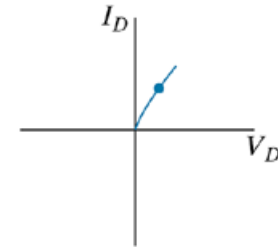
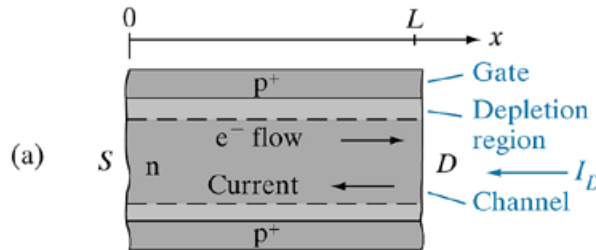
(b)

If  $V_G$  is increased or decreased by 0.25 V,  $V_D$  will increase or decrease by  $\sim 2$  volts.

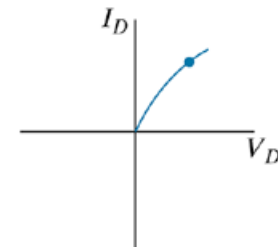
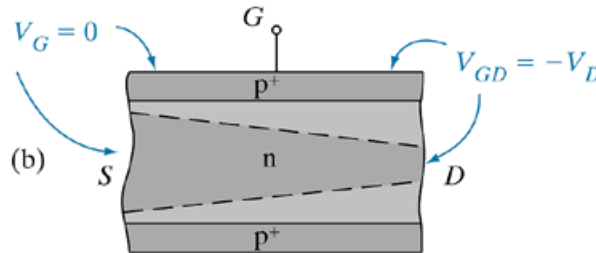
$$\text{Gain} = V_{\text{out}}/V_{\text{in}} = 8.$$

# JFET Operating Regions

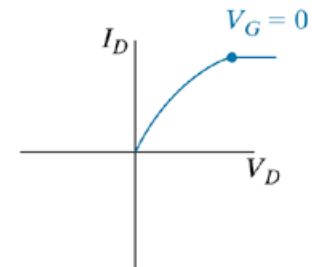
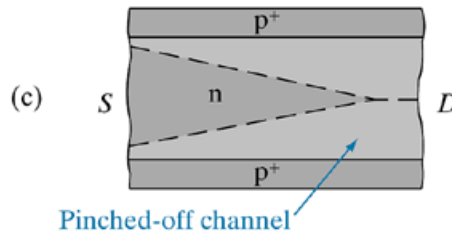
Linear region



Approaching Pinchoff

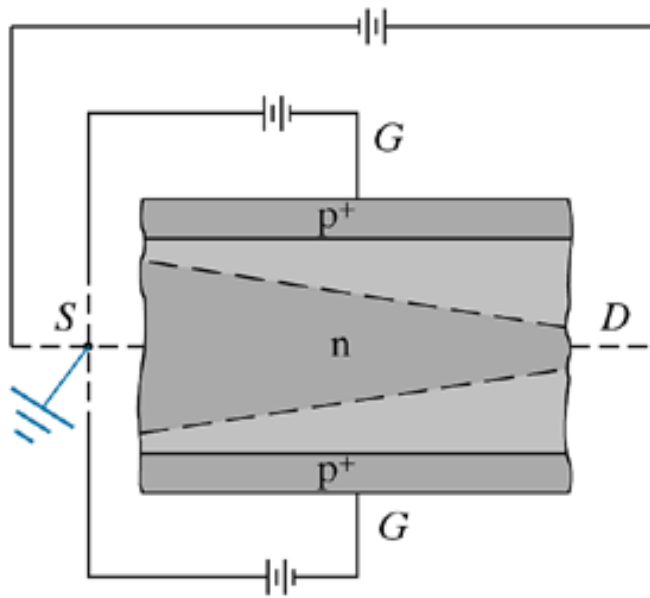


Beyond Pinchoff

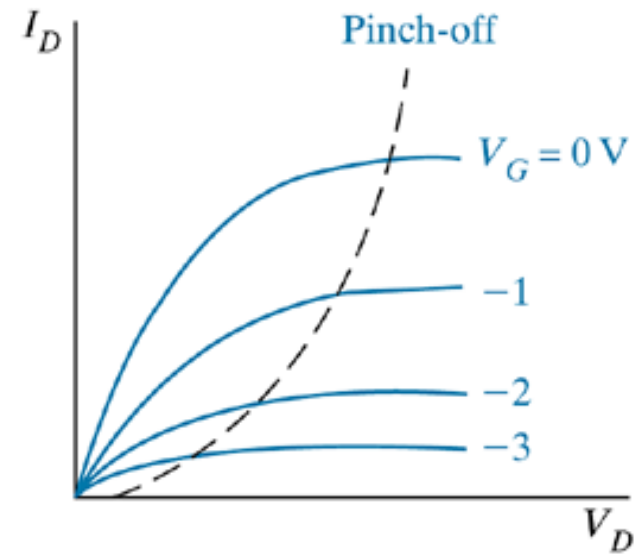


*Source* is the region from which the majority carriers flow. They flow to the *Drain*.

# Family of Curves



(a)



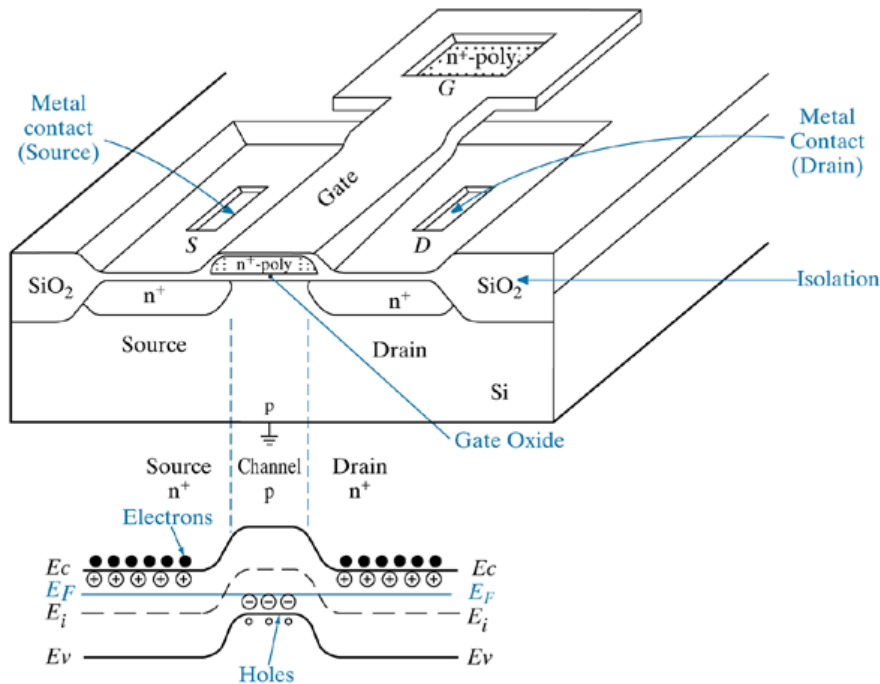
(b)

$V_G$  determines the operating curve

$V_D$  determines the region (linear, approaching saturation, pinch-off) of operation.



# MOSFET Band Diagram



## Equilibrium

Invariant Fermi level bends the p-type valence band up, creating an energy barrier to electron/hole flow.

## Positive Gate Voltage flattens the barrier

At  $V_T$  (threshold voltage)  
Allows current to flow with proper source to drain bias

# N-Channel MOSFET Operating Regions

Linear Region

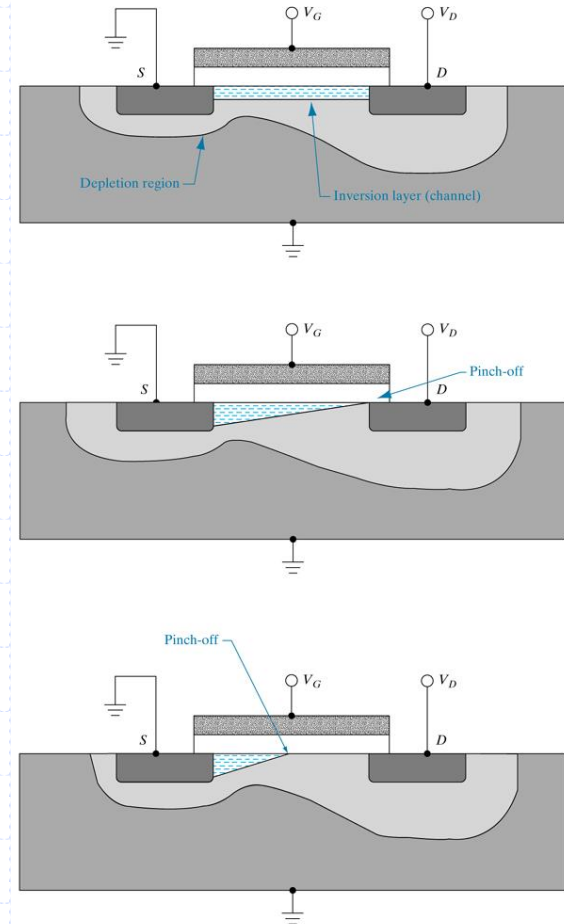
$$V_G > V_T \text{ and } V_D < (V_G - V_T)$$

Saturation onset

$$V_G > V_T \text{ and } V_D = (V_G - V_T)$$

Strong Saturation

$$V_G > V_T \text{ and } V_D > (V_G - V_T)$$

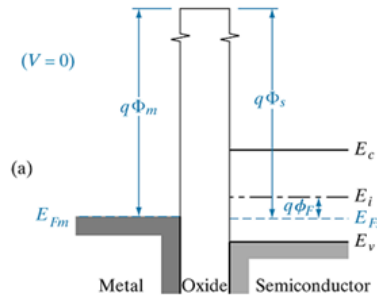


# How to Build a MOSFET

<http://microscopy.fsu.edu/electromag/java/transistor/index.html>

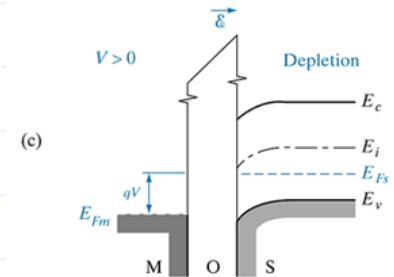
# N-Channel Formation in P type Material

Equilibrium  
 $V_G = 0$

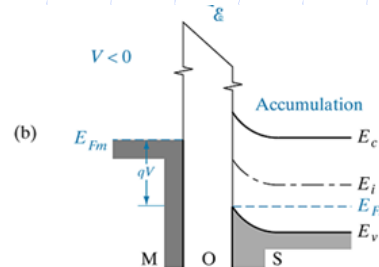


(M)etal = gate  
(O)xide = gate oxide  
(S)emiconductor = p-type

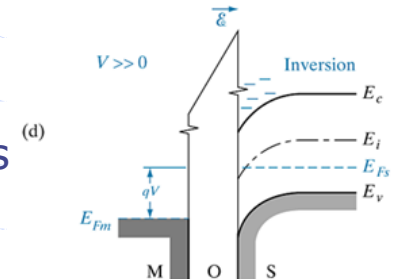
Depletion  
 $V_G > 0$ , repels holes  
from surface region



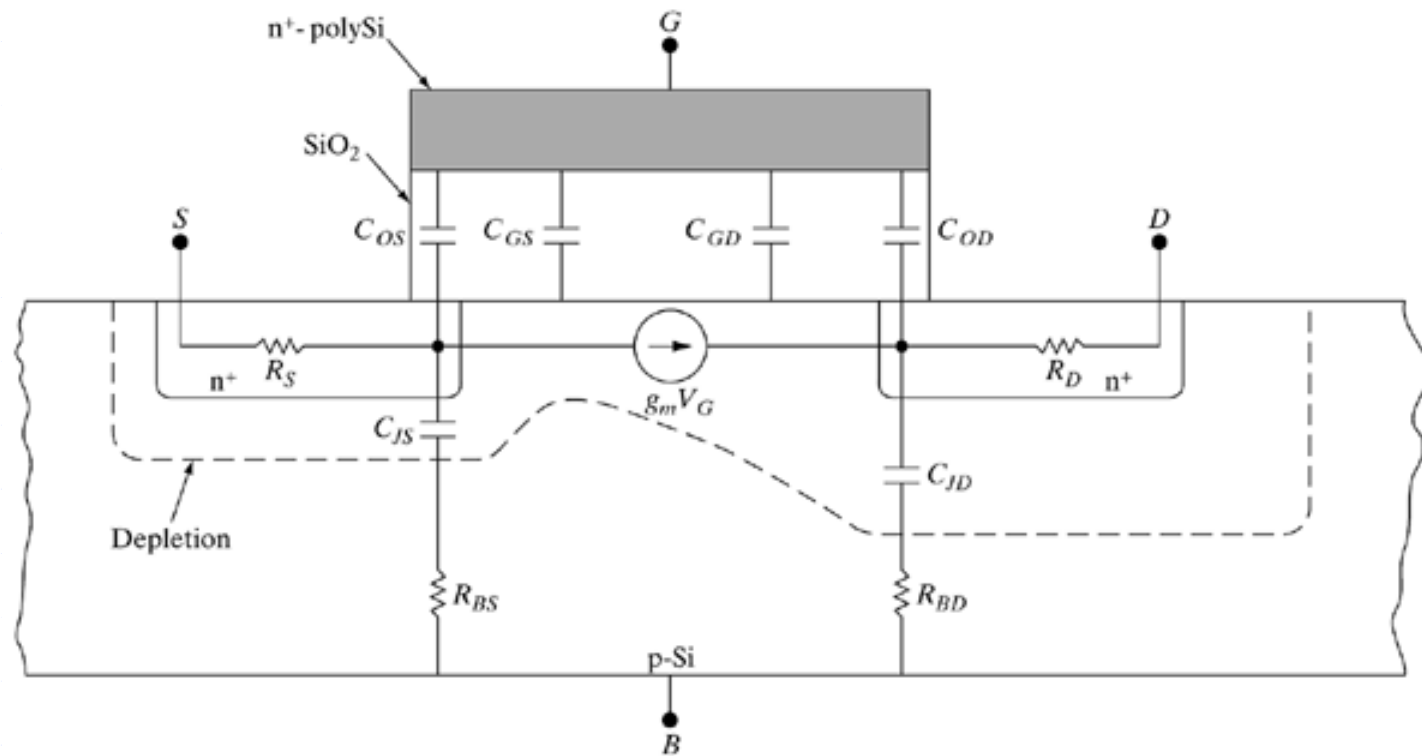
Accumulation  
 $V_G < 0$ , attracts holes  
to surface region



Inversion  
 $V_G \gg 0$ , attracts electrons  
to surface region,  
making it "N type"



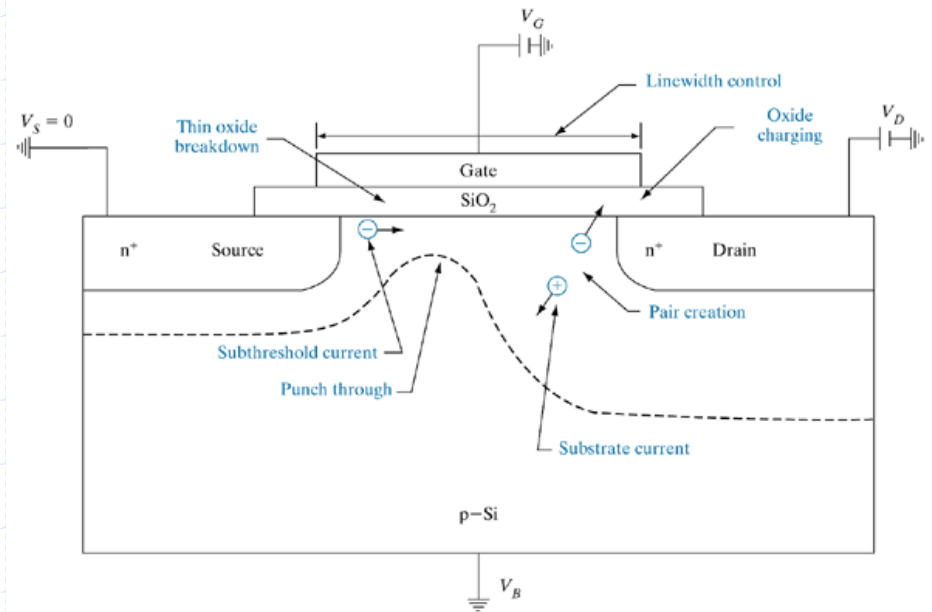
# MOSFET Equivalent Circuit



# MOSFET Short-Channel Effects

Shorter channels incur higher electric fields and current densities.

- Charge accumulates within the gate oxide due to hot carrier generation
- Unwanted (leakage) current flows due to punchthrough from the source to the drain
- Devices fail catastrophically due to thin gate oxide breakdown (rupture)



# Threshold Shift due to Hot Carriers

"Hot" electrons are "trapped" in the gate dielectric, imparting a permanent charge and subsequent threshold shift, as shown in these before and after I-V curves.

